

AUIRFR120Z AUIRFU120Z

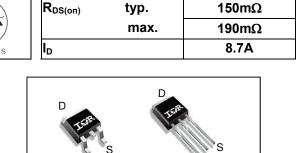
100V

Features

- Advanced Process Technology
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Tjmax
- Lead-Free, RoHS Compliant
- Automotive Qualified *

Description

Specifically designed for Automotive applications, this HEXFET[®] Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety of other applications.



D-Pak AUIRFR120Z

 V_{DSS}

I-Pak AUIRFU120Z

G	D	S
Gate	Drain	Source

Been nort number	Dookogo Turoo	Standard Pack		Ordershie Port Number
Base part number	Package Type	Form	Quantity	Orderable Part Number
AUIRFU120Z	I-Pak	Tube	75	AUIRFU120Z
AUIRFR120Z	D-Pak	Tube	75	AUIRFR120Z
AUIKER1202	D-Fak	Tape and Reel Left	3000	AUIRFR120ZTRL

Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	8.7	
I _D @ T _C = 100°C	$I_D @ T_C = 100^{\circ}C$ Continuous Drain Current, $V_{GS} @ 10V$		A
I _{DM}	Pulsed Drain Current ①	35	
P _D @T _C = 25°C	Maximum Power Dissipation	35	W
	Linear Derating Factor	0.23	W/°C
V _{GS}	Gate-to-Source Voltage	± 20	V
E _{AS}	Single Pulse Avalanche Energy (Thermally Limited) 2	18	m
E _{AS} (Tested)	Single Pulse Avalanche Energy Tested Value 6	20	mJ
I _{AR}	Avalanche Current ①	See Fig.15,16, 12a, 12b	A
E _{AR}	Repetitive Avalanche Energy S		mJ
TJ	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	

Thermal Resistance

Symbol	Parameter	Тур.	Max.	Units
R _{θJC}	Junction-to-Case		4.28	
$R_{ ext{ heta}JA}$	Junction-to-Ambient (PCB Mount) 🗇		50	°C/W
$R_{ ext{ heta}JA}$	Junction-to-Ambient		110	

HEXFET® is a registered trademark of Infineon.

*Qualification standards can be found at www.infineon.com



AUIRFR/U120Z

Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	100		_	V	V _{GS} = 0V, I _D = 250µA
$\Delta V_{(BR)DSS} / \Delta T_J$	Breakdown Voltage Temp. Coefficient		0.084		V/°C	Reference to 25°C, I_D = 1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance		150	190	mΩ	V _{GS} = 10V, I _D = 5.2A ③
V _{GS(th)}	Gate Threshold Voltage	2.0		4.0	V	V _{DS} = V _{GS} , I _D = 250μA
gfs	Forward Trans conductance	16			S	V _{DS} = 25V, I _D = 5.2A
1	Drain-to-Source Leakage Current			20	μA	V _{DS} = 100 V, V _{GS} = 0V
IDSS	Drain-to-Source Leakage Current			250	μΑ	V _{DS} = 100V,V _{GS} = 0V,T _J =125°C
1	Gate-to-Source Forward Leakage			200	n A	V _{GS} = 20V
I _{GSS}	Gate-to-Source Reverse Leakage			-200	nA	V _{GS} = -20V

Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

Q _g	Total Gate Charge		6.9	10		I _D = 5.2A
Q _{gs}	Gate-to-Source Charge		1.6	_	nC	V _{DS} = 80V
Q _{gd}	Gate-to-Drain Charge		3.1			V _{GS} = 10V③
t _{d(on)}	Turn-On Delay Time		8.3			V _{DD} = 50V
t _r	Rise Time		26		-	I _D = 5.2A
t _{d(off)}	Turn-Off Delay Time		27		ns	R _G = 53Ω
t _f	Fall Time		23			V _{GS} = 10V③
L _D	Internal Drain Inductance		4.5			Between lead, 6mm (0.25in.)
L _S	Internal Source Inductance		7.5		1111	from package and center of die contact
C _{iss}	Input Capacitance		310			V _{GS} = 0V
C _{oss}	Output Capacitance		41			V _{DS} = 25V
C _{rss}	Reverse Transfer Capacitance		24		pF	<i>f</i> = 1.0MHz
C _{oss}	Output Capacitance		150		pr	$V_{GS} = 0V, V_{DS} = 1.0V f = 1.0MHz$
C _{oss}	Output Capacitance		26			$V_{GS} = 0V, V_{DS} = 80V f = 1.0MHz$
C _{oss eff.}	Effective Output Capacitance		57			$V_{GS} = 0V, V_{DS} = 0V \text{ to } 80V @$
Diode Chara	cteristics					
	Parameter	Min.	Тур.	Max.	Units	Conditions
	Continuous Source Current			0.7		MOSFET symbol

ls	Continuous Source Current (Body Diode)			8.7	•	MOSFET symbol showing the
I _{SM}	Pulsed Source Current (Body Diode) ①			35	A	integral reverse p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	T _J = 25°C,I _S = 5.2A,V _{GS} = 0V ③
t _{rr}	Reverse Recovery Time		24	36	ns	T _J = 25°C ,I _F = 5.2A, V _{DD} = 50V
Q _{rr}	Reverse Recovery Charge		23	35	nC	di/dt = 100A/µs③
t _{on}	Forward Turn-On Time	Intrinsio	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)			

Notes:

① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)

② Limited by T_{Jmax} , starting T_J = 25°C, L = 1.29mH, R_G = 25Ω, I_{AS} = 5.2A, V_{GS} =10V. Part not recommended for use above this value. ③ Pulse width ≤ 1.0ms; duty cycle ≤ 2%.

- ④ Coss eff. is a fixed capacitance that gives the same charging time as Coss while VDS is rising from 0 to 80% VDSS
- Imited by T_{Jmax} , see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- © This value determined from sample failure population. 100% tested to this value in production.
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994



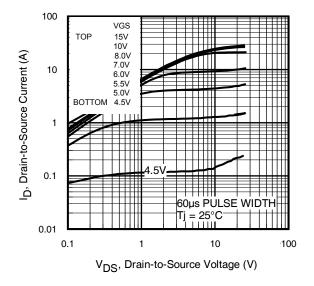


Fig. 1 Typical Output Characteristics

Fig. 2 Typical Output Characteristics

V_{DS}, Drain-to-Source Voltage (V)

.5V

60µs PULSE WIDTH Tj = 175°C | | | |

100

10



100

10

1

0.1

0.1

I_D, Drain-to-Source Current (A)

VGS

15V 10V

8.0V 7.0V

6.0V 5.5V 5.0V 4.5V

1

TOP

BOTTOM

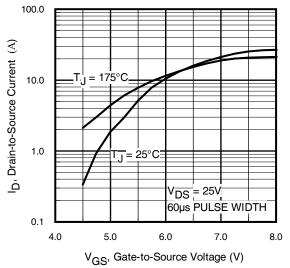
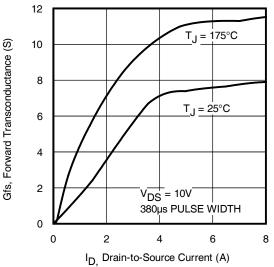
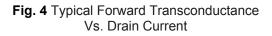
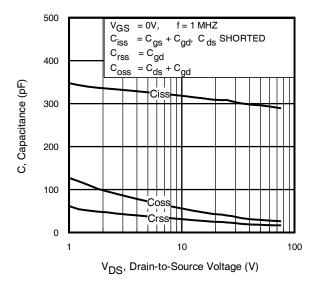


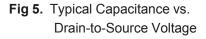
Fig. 3 Typical Transfer Characteristics











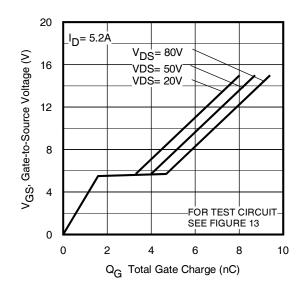


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

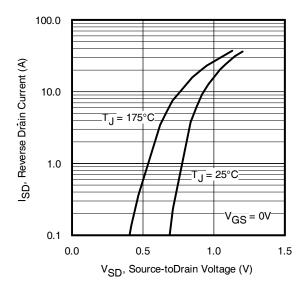


Fig. 7 Typical Source-to-Drain Diode Forward Voltage

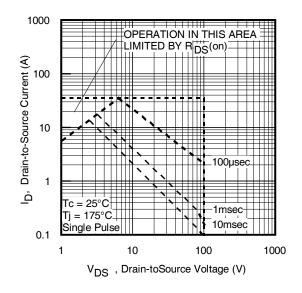


Fig 8. Maximum Safe Operating Area



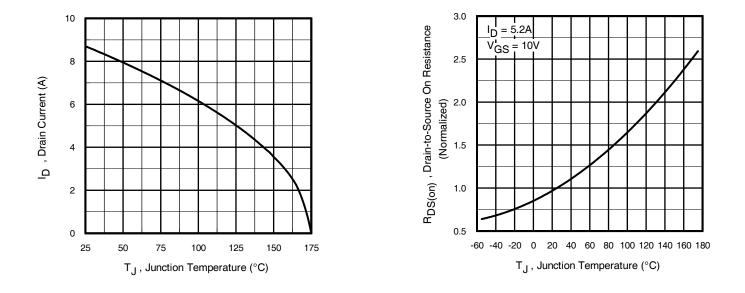


Fig 9. Maximum Drain Current Vs. Case Temperature

Fig 10. Normalized On-Resistance Vs. Temperature

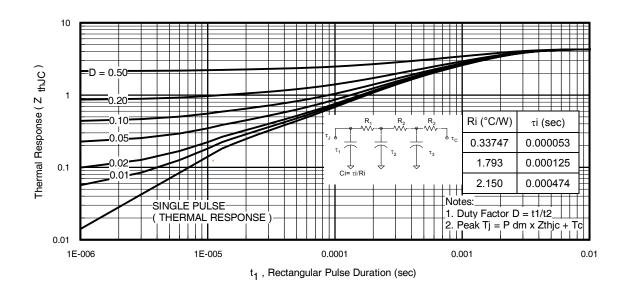


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

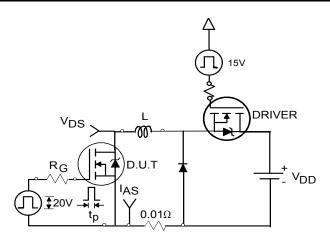


Fig 12a. Unclamped Inductive Test Circuit

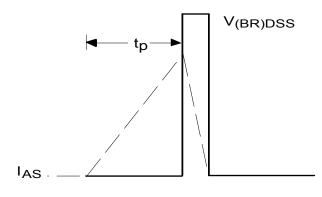


Fig 12b. Unclamped Inductive Waveforms

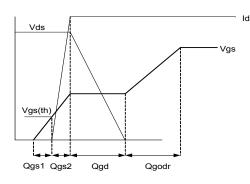


Fig 13a. Gate Charge Waveform

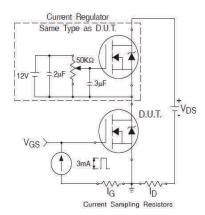
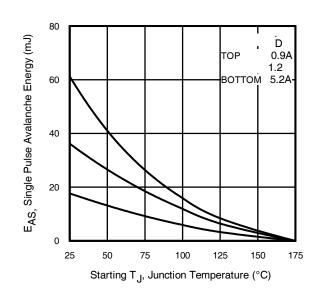
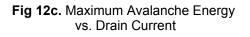


Fig 13b. Gate Charge Test Circuit





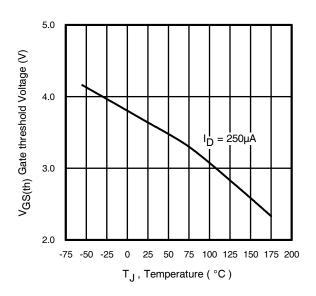


Fig 14. Threshold Voltage Vs. Temperature

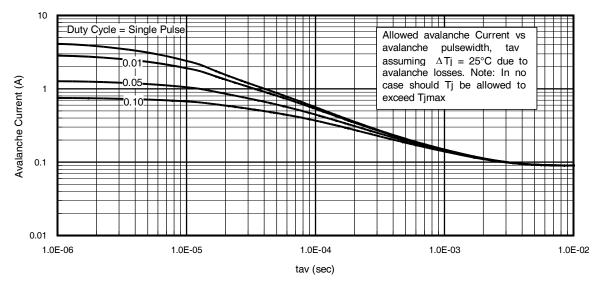
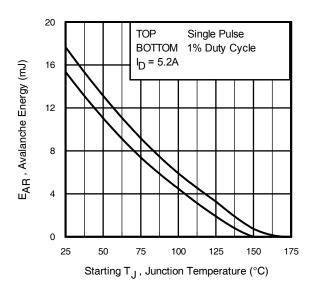
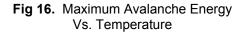


Fig 15. Typical Avalanche Current Vs.Pulsewidth





Notes on Repetitive Avalanche Curves , Figures 15, 16:

(For further info, see AN-1005 at www.infineon.com)

- Avalanche failures assumption: Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{imax}. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long as T_{jmax} is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- 4. PD (ave) = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. Iav = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 15, 16).

tav = Average time in avalanche.

D = Duty cycle in avalanche = tav ·f

ZthJC(D, tav) = Transient thermal resistance, see Figures 13)

$$\begin{split} \textbf{P}_{D (ave)} &= 1/2 \; (\; \textbf{1.3} \cdot \textbf{BV} \cdot \textbf{I}_{av}) = \Delta T/ \; \textbf{Z}_{thJC} \\ \textbf{I}_{av} &= 2\Delta T/ \; [\textbf{1.3} \cdot \textbf{BV} \cdot \textbf{Z}_{th}] \\ \textbf{E}_{AS (AR)} &= \textbf{P}_{D (ave)} \cdot \textbf{t}_{av} \end{split}$$

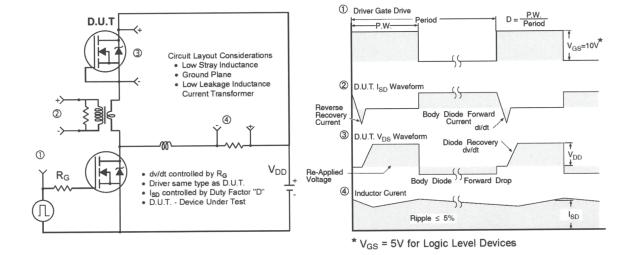


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

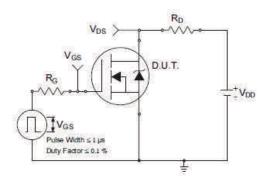


Fig 18a. Switching Time Test Circuit

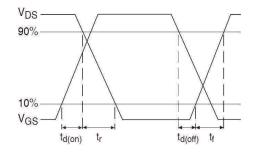
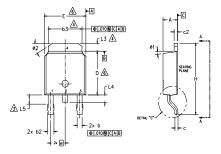


Fig 18b. Switching Time Waveforms

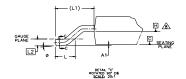


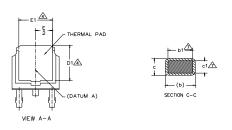
AUIRFR/U120Z

D-Pak (TO-252AA) Package Outline (Dimensions are shown in millimeters (inches))









NOTES:

- 1.- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2.- DIMENSION ARE SHOWN IN INCHES [MILLIMETERS].
- A- LEAD DIMENSION UNCONTROLLED IN L5.
- A- DIMENSION D1, E1, L3 & 63 ESTABLISH A MINIMUM MOUNTING SURFACE FOR THERMAL PAD.
- SECTION C-C DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN .005 AND 0.10 [0.13 AND 0.25] FROM THE LEAD TIP.
- ▲ DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005 [0.13] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- A- DIMENSION 61 & c1 APPLIED TO BASE METAL ONLY.
- A- DATUM A & B TO BE DETERMINED AT DATUM PLANE H.

9	OUTLINE	CONFORMS	TO	JEDEC	OUTLINE	T0-	-252AA.	
-							1	

S Y		N			
M B O	MILLIM	ETERS	INC	HES	N O T
0 L	MIN.	MAX.	MIN.	MAX.	E S
А	2.18	2.39	.086	.094	
A1	-	0.13	-	.005	
b	0.64	0.89	.025	.035	
ь1	0.65	0.79	.025	.031	7
b2	0.76	1.14	.030	.045	
b3	4.95	5.46	.195	.215	4
с	0.46	0.61	.018	.024	
c1	0.41	0.56	.016	.022	7
c2	0.46	0.89	.018	.035	
D	5.97	6.22	.235	.245	6
D1	5.21	-	.205	-	4
Е	6.35	6.73	.250	.265	6
E1	4.32	-	.170	-	4
е	2.29	BSC	.090	BSC	
н	9.40	10.41	.370	.410	
L	1.40	1.78	.055	.070	
L1	2.74	BSC	.108	REF.	
L2	0.51	BSC	.020	BSC	
L3	0.89	1.27	.035	.050	4
L4	-	1.02	-	.040	
L5	1.14	1.52	.045	.060	3
ø	0.	10 °	0.	10°	
ø1	0.	15 °	0.	15°	
ø2	25'	35*	25*	35*	

LEAD ASSIGNMENTS

<u>HEXFET</u>

1.- GATE 2.- DRAIN 3.- SOURCE 4.- DRAIN

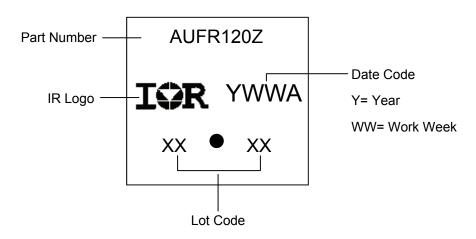
IGBT & CoPAK

1.- GATE

2.- COLLECTOR 3.- EMITTER

4.- COLLECTOR

D-Pak (TO-252AA) Part Marking Information

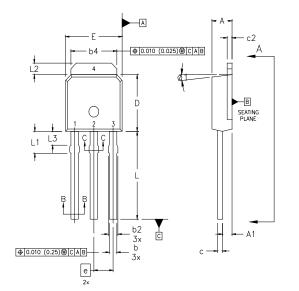


Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



AUIRFR/U120Z

I-Pak (TO-251AA) Package Outline (Dimensions are shown in millimeters (inches)



NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5 M- 1994. 1
- 2
- DIMENSION ARE SHOWN IN MILLIMETERS [INCHES]. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY. 3
- THERMAL PAD CONTOUR OPTION WITHIN DIMENSION 64, L2, E1 & D1. 4 LEAD DIMENSION UNCONTROLLED IN L3. 5
- 6 DIMENSION 61, 63 APPLY TO BASE METAL ONLY.
- OUTLINE CONFORMS TO JEDEC OUTLINE TO-251AA.

8 CONTROLLING DIMENSION : INCHES.

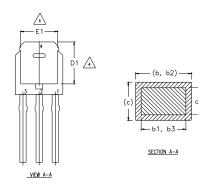
LEAD ASSIGNMENTS

HEXFET

1.- GATE

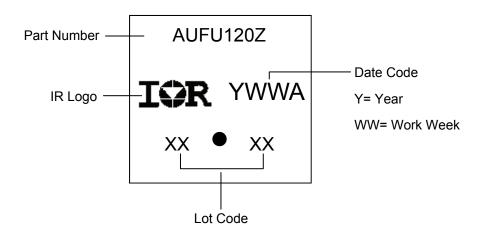
2.- DRAIN 3.- SOURCE





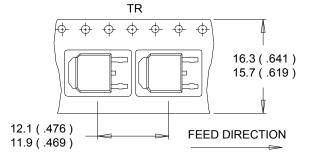
SYMBOL	MILLIM	ETERS	INC	INCHES	
	Min.	MAX.	MIN.	MAX.	NOTES
A	2.18	2.39	0.086	.094	
A1	0.89	1.14	0.035	0.045	
b	0.64	0.89	0.025	0.035	
ь1	0.64	0.79	0.025	0.031	4
b2	0.76	1.14	0.030	0.045	
b3	0.76	1.04	0.030	0.041	
b4	5.00	5.46	0.195	0.215	4
с	0.46	0.61	0.018	0.024	
c1	0.41	0.56	0.016	0.022	
c2	.046	0.86	0.018	0.035	
D	5.97	6.22	0.235	0.245	3, 4
D1	5.21	-	0.205	-	4
E	6.35	6.73	0.250	0.265	3, 4
E1	4.32	-	0.170	-	4
е	2.29		0.090	BSC	
L	8.89	9.60	0.350	0.380	
L1	1.91	2.29	0.075	0.090	
L2	0.89	1.27	0.035	0.050	4
L3	1.14	1.52	0.045	0.060	5
ø1	0.	15	0.	15*	

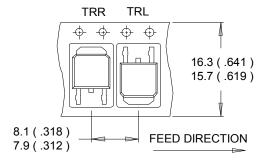
I-Pak (TO-251AA) Part Marking Information



Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

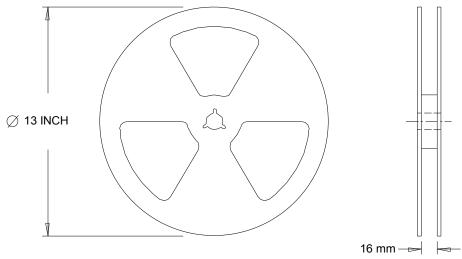
D-Pak (TO-252AA) Tape & Reel Information (Dimensions are shown in millimeters (inches))





NOTES :

- 1. CONTROLLING DIMENSION : MILLIMETER.
- 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
- 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES :

1. OUTLINE CONFORMS TO EIA-481.

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



Qualification Information

		Automotive (per AEC-Q101)				
			is part number(s) passed Automotive qualification. Infineon's consumer qualification level is granted by extension of the higher			
Maiatura			MSL1			
Moisture	Sensitivity Level	I-Pak	MISE I			
			Class M1B (+/- 100V) [†]			
	Machine Model	AEC-Q101-002				
505		Class H0 (+/- 100V) [†]				
ESD	Human Body Model	AEC-Q101-001				
			Class C5 (+/- 2000V) [†]			
	Charged Device Model	AEC-Q101-005				
RoHS Co	mpliant		Yes			

† Highest passing voltage.

Revision History

Date	Comments			
10/12/2015	Updated datasheet with corporate template			
10/12/2015	Corrected ordering table on page 1.			

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